. •	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/796,090	TAKE, KEIJIRO
Examiner	Art Unit
IriH. Phan	2661

	SEARCHED			
Class	Subclass	Date	Examiner	
370	320,335, 342,441, 479,203	11/30/2004	TP	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1.			

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
EAST, IEEE, Internet searched	11/30/2004	TP
Consulted with Sam Phirin (Pri)	4/7/2005	TP
Updated search	6/17/2005	TP
Eat	12/20/05	BN

